



### General Description:

CS10J65F A9-G, the silicon N-channel Enhanced MOSFETs, is obtained by the super junction technology which reduces the conduction loss, improve switching performance and enhance the avalanche energy.

The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

The package type is TO-220F, which accords with the RoHS standard.

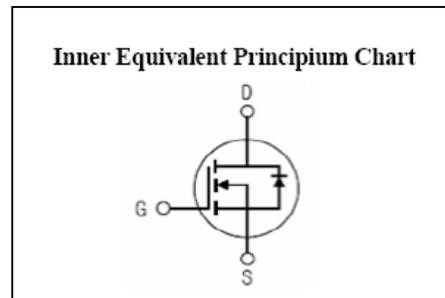
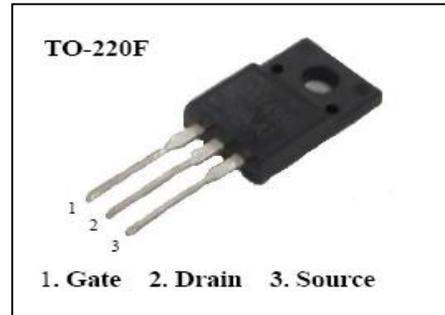
### Features:

- | Fast Switching
- | Low Gate Charge
- | Low Reverse transfer capacitances
- | 100% Single Pulse avalanche energy Test
- | Halogen Free

### Applications:

- | Power switch circuit of adaptor and charger.

$V_{DSS}$	650	V
$I_D$	10	A
$P_D(T_C=25^\circ\text{C})$	30	W
$R_{DS(ON)max}$	0.62	$\Omega$



**Absolute** ( $T_c=25^\circ\text{C}$  unless otherwise specified):

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-to-Source Voltage	650	V
$I_D$	Continuous Drain Current	10	A
$I_{DM}^{a1}$	Pulsed Drain Current	30	A
$V_{GS}$	Gate-to-Source Voltage	$\pm 30$	V
$E_{AS}^{a2}$	Single Pulse Avalanche Energy	50	mJ
$P_D$	Power Dissipation	30	W
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	$-55 \dots +150$	$^\circ\text{C}$

**Electrical Characteristics** (Tc= 25°C unless otherwise specified):

<b>OFF Characteristics</b>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V <sub>DSS</sub>	Drain to Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	650	--	--	V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 650V, V <sub>GS</sub> = 0V, T <sub>a</sub> = 25°C	--	--	1	μA
		V <sub>DS</sub> =650V, V <sub>GS</sub> = 0V, T <sub>a</sub> = 125°C	--	--	100	
I <sub>GSS(F)</sub>	Gate to Source Forward Leakage	V <sub>GS</sub> =+30V	--	--	100	nA
I <sub>GSS(R)</sub>	Gate to Source Reverse Leakage	V <sub>GS</sub> =-30V	--	--	-100	nA

<b>ON Characteristics</b>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R <sub>DS(ON)</sub>	Drain-to-Source On-Resistance	V <sub>GS</sub> =10V,I <sub>D</sub> =3A	--	0.54	0.62	Ω
V <sub>GS(TH)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2.5		4	V

<b>Dynamic Characteristics</b>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g <sub>fs</sub>	Forward Trans conductance	V <sub>DS</sub> =10V, I <sub>D</sub> =3A	--	5.6	--	S
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V V <sub>DS</sub> = 50V f = 1.0MHz	--	450	--	pF
C <sub>oss</sub>	Output Capacitance		--	63	--	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	3.7	--	

<b>Resistive Switching Characteristics</b>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t <sub>d(ON)</sub>	Turn-on Delay Time	I <sub>D</sub> = 7 A V <sub>DD</sub> = 300V R <sub>θ</sub> =25Ω	--	14	31	ns
t <sub>r</sub>	Rise Time		--	32	66	
t <sub>d(OFF)</sub>	Turn-Off Delay Time		--	53	109	
t <sub>f</sub>	Fall Time		--	15	32	
Q <sub>g</sub>	Total Gate Charge	I <sub>D</sub> = 7 A V <sub>DD</sub> =480V V <sub>GS</sub> = 10V	--	10	--	nC
Q <sub>gs</sub>	Gate to Source Charge		--	2	--	
Q <sub>gd</sub>	Gate to Drain (“Miller”)Charge		--	3.7	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$I_S$	Continuous Source Current (Body Diode)		--		10	A
$I_{SM}$	Maximum Pulsed Current (Body Diode)		--		20	A
$V_{SD}$	Diode Forward Voltage	$I_S=7A, V_{GS}=0V$	--	0.9	1.2	V
$t_{rr}$	Reverse Recovery Time	$I_f=I_S \quad I_r/dt=100A/us$	--	400		ns
$Q_{rr}$	Reverse Recovery Charge		--	1.5		$\mu C$

Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case	4.17	$^{\circ}C/W$
$R_{\theta JA}$	Junction-to-Ambient	80	$^{\circ}C/W$

<sup>a1</sup>: Repetitive rating; pulse width limited by maximum junction temperature

<sup>a2</sup>:  $L=10.0mH, R_g=25 \Omega, V_{dd}=50V, Start T_J=25^{\circ}C$

Characteristics Curve:

Figure 1. Output Characteristics

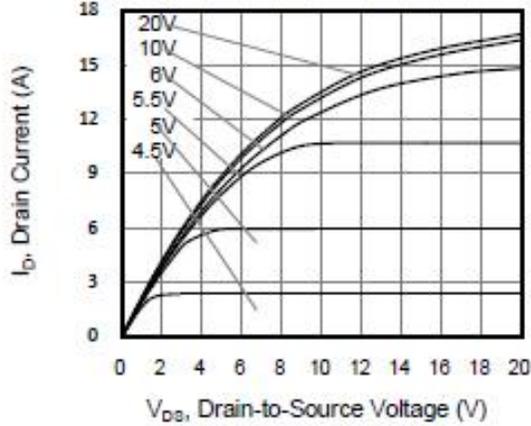


Figure 2. Transfer Characteristics

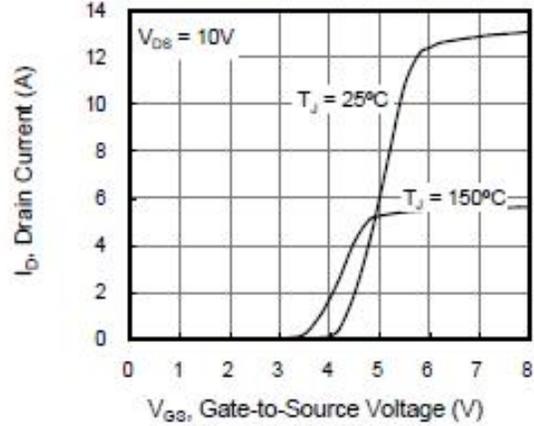


Figure 3. On-Resistance vs. Drain Current

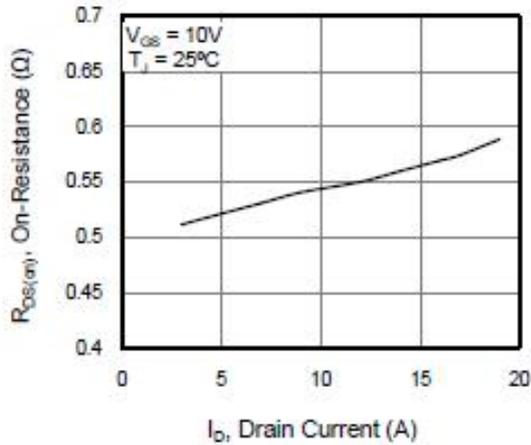


Figure 4. Capacitance

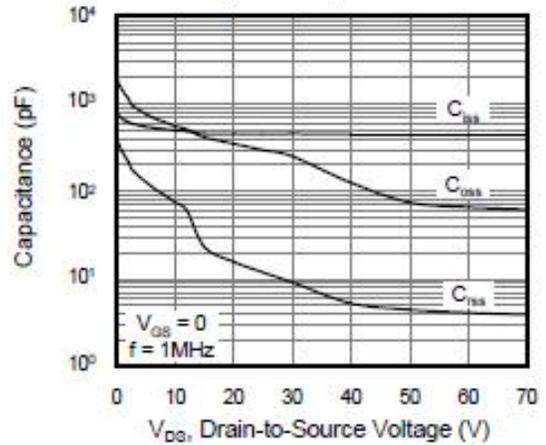


Figure 5. Gate Charge

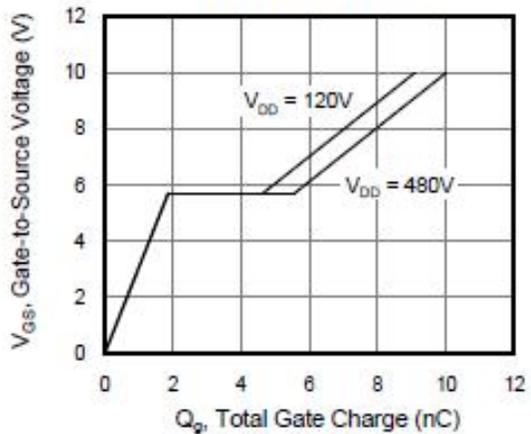


Figure 6. Body Diode Forward Voltage

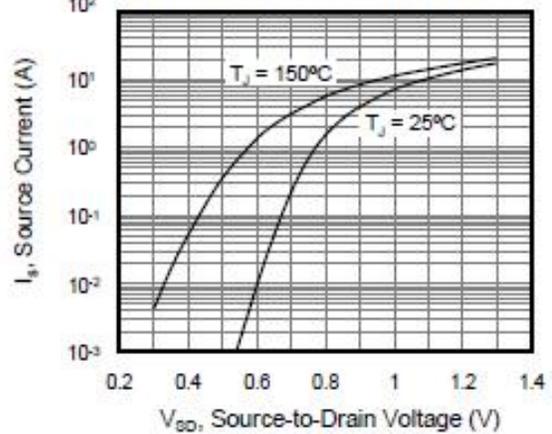


Figure 7. On-Resistance vs. Junction Temperature

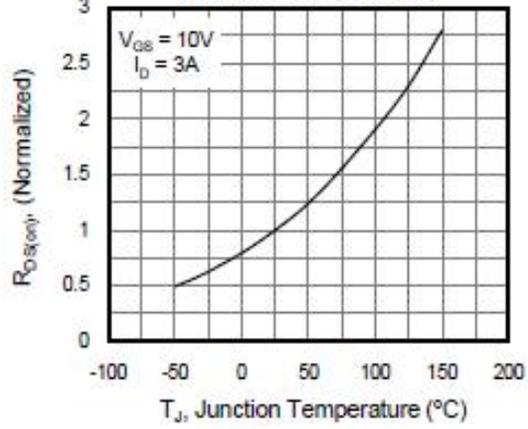
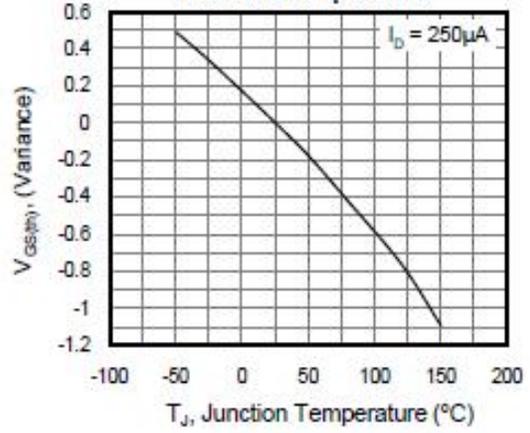
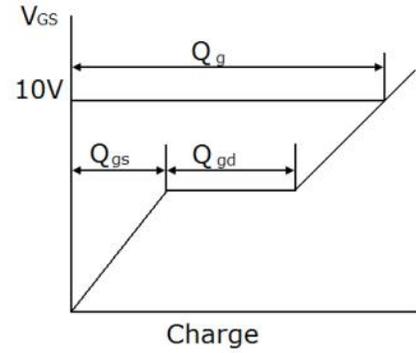
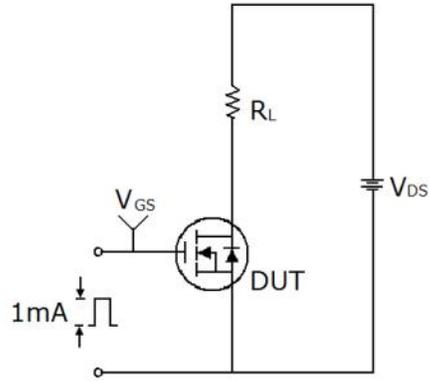


Figure 8. Threshold Voltage vs. Junction Temperature

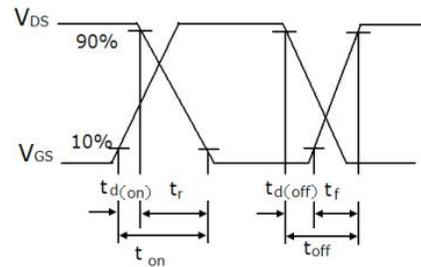
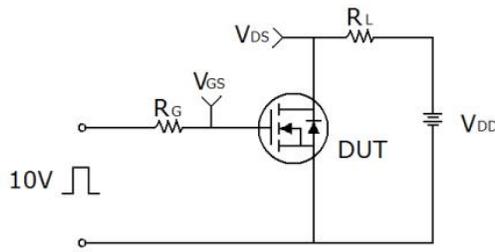


**Test Circuit and Waveform:**

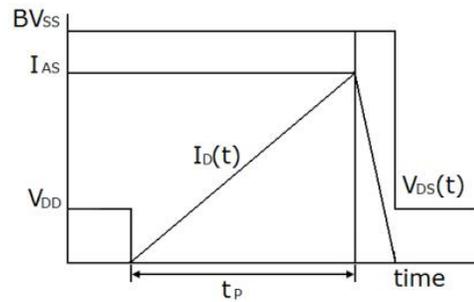
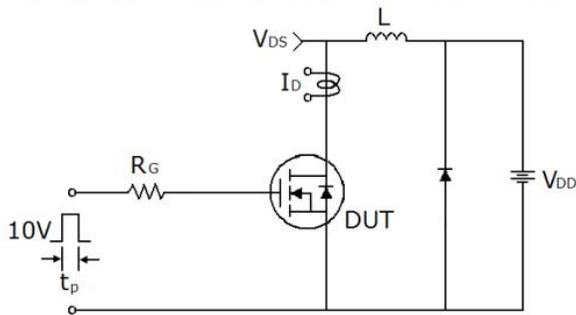
**1) Gate charge test circuit & Waveform**



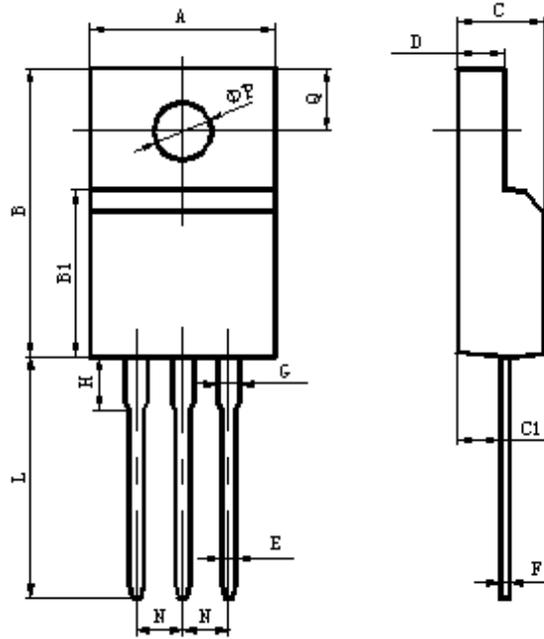
**2) Switch Time Test Circuit:**



**3) Unclamped Inductive Switching Test Circuit & Waveforms**



**Package Information:**



Items	Values(mm)	
	MIN	MAX
A	9.60	10.4
B	15.4	16.2
B1	8.90	9.50
C	4.30	4.90
C1	2.10	3.00
D	2.40	3.00
E	0.60	1.00
F	0.30	0.60
G	1.12	1.42
H	3.40	3.80
	2.40	2.90
L	12.0	14.0
	6.30	7.70
N	2.34	2.74
Q	3.15	3.55
φ P	2.90	3.30

TO-220F Package

**The name and content of poisonous and harmful material in products**

Part's Name	Hazardous Substance									
	Pb	Hg	Cd	Cr(VI)	PBB	PBDE	DIBP	DEHP	DBP	BBP
Limit	≤0.1%	≤0.1%	≤ 0.01%	≤0.1%	≤0.1%	≤0.1%	≤0.1%	≤0.1%	≤0.1%	≤0.1%
Lead Frame	○	○	○	○	○	○	○	○	○	○
Molding	○	○	○	○	○	○	○	○	○	○
Chip	○	○	○	○	○	○	○	○	○	○
Wire Bonding	○	○	○	○	○	○	○	○	○	○
Solder	×	○	○	○	○	○	○	○	○	○
Note	○: means the hazardous material is under the criterion of SJ/T11363-2006. ×: means the hazardous material exceeds the criterion of SJ/T11363-2006. The plumbum element of solder exist in products presently, but within the allowed range of Eurogroup's RoHS.									

**Warnings**

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. It is suggested to be used under 80 percent of the maximum ratings of the device.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. VDMOSFET is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. This publication is made by Huajing Microelectronics and subject to regular change without notice.

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